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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/802,549	03/16/2004	Eitan Cadouri	524322000600	3719

56702 7590 06/14/2006

PDF SOLUTIONS c/o MOFO SF  
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EXAMINER

DANG, PHUC T

ART UNIT PAPER NUMBER

2818

DATE MAILED: 06/14/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

**Office Action Summary**

Application No.

10/802,549

Applicant(s)

CADOURI, EITAN

Examiner

PHUC T. DANG

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-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

**Period for Reply**

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

**Status**

- 1) ☒ Responsive to communication(s) filed on amendment filed April 7, 2006.
- 2a) ☐ This action is **FINAL**. 2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

**Disposition of Claims**

- 4) ☒ Claim(s) 1-15 and 21-25 is/are pending in the application.
- 4a) Of the above claim(s) \_\_\_\_\_ is/are withdrawn from consideration.
- 5) ☒ Claim(s) 12-15 and 21-25 is/are allowed.
- 6) ☒ Claim(s) 1, 5 and 8 is/are rejected.
- 7) ☒ Claim(s) 2-4 and 6-11 is/are objected to.
- 8) ☐ Claim(s) \_\_\_\_\_ are subject to restriction and/or election requirement.

**Application Papers**

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☒ The drawing(s) filed on 16 March 2004 is/are: a) ☒ accepted or b) ☐ objected to by the Examiner.  
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).  
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

**Priority under 35 U.S.C. § 119**

- 12) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All b) ☐ Some \* c) ☐ None of:
- ☐ Certified copies of the priority documents have been received.
  - ☐ Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.
  - ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

\* See the attached detailed Office action for a list of the certified copies not received.

**Attachment(s)**

- |  |   |
|--|---|
| 1) <input checked="" type="checkbox"/> Notice of References Cited (PTO-892)  | 4) <input type="checkbox"/> Interview Summary (PTO-413)<br>Paper No(s)/Mail Date. _____ |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948)                                   | 5) <input type="checkbox"/> Notice of Informal Patent Application (PTO-152)             |
| 3) <input type="checkbox"/> Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)<br>Paper No(s)/Mail Date _____ | 6) <input type="checkbox"/> Other: _____  |

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## **DETAILED ACTION**

### **Response to Arguments**

1. Applicant's arguments filed on April 7, 2006 have been fully considered but that are not persuasive and Applicant's arguments with respect to claims 1-15 and 21-25 have been considered but are moot in view of the new ground(s) of rejection.

### **Claim Rejections - 35 USC § 102**

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein were made absent any evidence to the contrary. Applicant is advised of the obligation under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was not commonly owned at the time a later invention was made in order for the examiner to consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(f) or (g) prior art under 35 U.S.C. 103(a).

2. Claims 1, 5 and 8 are rejected under 35 U.S.C. 102 (e) as being anticipated by Tseng (U.S. Publication No. US 2003/0094965 A1).

Regarding claim 1, Tseng discloses a method of adjusting a die placement of dice to be formed on a wafer comprising:

a) obtaining a die placement of die to be formed on the wafer by probe testing [Figs. 1-2].

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b) obtaining one or more locations on the wafer contacted by one or more processing structures or a substance emitted by one or more processing structures by probe testing [Fig. 2].

c) adjusting the die placement based on the obtained one or more locations on the wafer by probe retesting [Fig. 3 and paragraph [0039]-[0049]].

Regarding claim 5, Tseng discloses adjusting the one or more locations on the wafer based on the die placement, wherein the die placement and the one or more locations on the wafer are adjusted together [Figs. 1-3].

Regarding claim 8, Tseng discloses the die placement includes an arrangement of the reticle array, wherein each reticle array includes an arrangement of dice [Figs. 1-4].

#### **Allowable Subject Matter**

3. Claims 12-15 and 21-25 would be allowed.

The following is a statement of reason for the indication of allowable subject matter:

Claims 12-15 and 21-25 are considered allowable since the prior art of record and the considered pertinent to the applicant's disclosure does not teach or suggest the claimed invention having one or more locations on the wafer contacted by one or more clamps as disclosed in claim 12 and adjusting the die placement based on the obtained one or more locations on the wafer, wherein the adjusted die placement produce a higher yield of dice formed on the wafer than the die placement obtained in step a) as disclosed in claim 21.

Claims 2-4, 6-7 and 9-11 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

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None of the Prior art of record does not disclose the die placement is adjusted to increase yield of the dice formed on the wafer as cited in claim 2 and the die placement and one or more locations on the wafer are adjusted to increase yield of the die formed on the wafer as cited in claim 6 and the one or more processing structures include a clamp to hold the wafer during a fabrication process as cited in claim 9 and the one or more processing structures include a jet that emits a chemical solution or water at the wafer as cited in claim 10 and the dice are formed on a first surface on the wafer, and wherein the one or more locations are on the first surface of the wafer or on a second surface on the wafer opposite the first surface as cited in claim 11.

Claims 3-4 and 7 are directly or indirectly depend on claims 2 and 6, then, they also would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

### **Conclusion**


4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Phuc T. Dang whose telephone number is 571-272-1776. The examiner can normally be reached on 8:00 am-5:00 pm.

5. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Minsun C. Harvey can be reached on (571) 272-1835. The fax phone numbers for the organization where this application or proceeding is assigned are 703-872-9306 for regular communications and Final communications.

6. Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is 703-308-0956.

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Phuc T. Dang

A handwritten signature in black ink, appearing to read 'Phuc T. Dang', written in a cursive style.

Primary Examiner

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